


<b>Search Notes</b>  	<b>Application/Control No.</b>  10620302	<b>Applicant(s)/Patent Under Reexamination</b>  GROVER ET AL.
	<b>Examiner</b>  GERMAN VIANA DI PRISCO	<b>Art Unit</b>  2617

### SEARCHED

Class	Subclass	Date	Examiner
370	218	5/31/2008	GV

### SEARCH NOTES

Search Notes	Date	Examiner
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM TDB (see attached search strategy)	5/31/2008	GV
Inventor name and Assignee search in PALM ExPO and EAST	5/31/2008	GV
Consulted with Rafael Perez-Gutierrez	5/31/2008	GV
IEEE Xplore Database( <a href="http://ieeexplore.ieee.org/Xplore/DynWel.jsp">http://ieeexplore.ieee.org/Xplore/DynWel.jsp</a> )	5/31/2008	GV

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner